

128M(8Mx16) GDDR SDRAM HY5DV281622DT



Revision History

Revision No.	History	Draft Date	Remark
0.1	Defined Preliminary Specification	May. 2002	
0.2	Defined Target AC, DC spec.	Nov. 2002	
0.3	Changed tCK_max. value of HY5DV281622DT-4/5/6 from 7.5ns to 7.0ns	Feb. 2003	
0.4	Changed VDD/VDDQ max range of HY5DV281622DT-33/36	Aug. 2003	
0.5	Changed tRAS_max Value from 120K to 100K in All Frequency	Aug. 2003	



DESCRIPTION

The Hynix HY5DV281622 is a 134,217,728-bit CMOS Double Data Rate(DDR) Synchronous DRAM, ideally suited for the point-to-point applications which requires high bandwidth.

The Hynix 8Mx16 DDR SDRAMs offer fully synchronous operations referenced to both rising and falling edges of the clock. While all addresses and control inputs are latched on the rising edges of the CK (falling edges of the /CK), Data, Data strobes and Write data masks inputs are sampled on both rising and falling edges of it. The data paths are internally pipelined and 2-bit prefetched to achieve very high bandwidth. All input and output voltage levels are compatible with SSTL 2.

FEATURES

- 3.3V for VDD and 2.5V for VDDQ power supply
- All inputs and outputs are compatible with SSTL_2 interface
- JEDEC standard 400mil 66pin TSOP-II with 0.65mm pin pitch
- Fully differential clock inputs (CK, /CK) operation
- Double data rate interface
- Source synchronous data transaction aligned to bidirectional data strobe (DQS)
- x16 device has 2 bytewide data strobes (LDQS, UDQS) per each x8 I/O
- Data outputs on DQS edges when read (edged DQ)
 Data inputs on DQS centers when write (centered DQ)
- Data(DQ) and Write masks(DM) latched on the both rising and falling edges of the data strobe

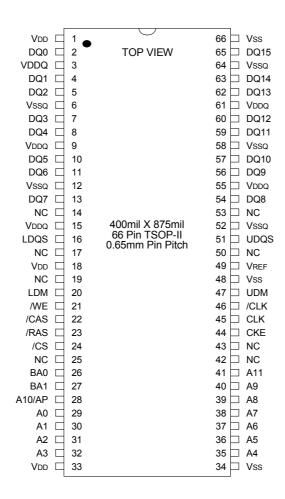
- All addresses and control inputs except Data, Data strobes and Data masks latched on the rising edges of the clock
- Write mask byte controls by LDM and UDM
- Programmable /CAS latency 3 / 4 supported
- Programmable Burst Length 2 / 4 / 8 with both sequential and interleave mode
- Internal 4 bank operations with single pulsed /RAS
- tRAS Lock-Out function supported
- Auto refresh and self refresh supported
- 4096 refresh cycles / 32ms
- Full, Half and Matched Impedance(Weak) strength driver option controlled by EMRS

ORDERING INFORMATION

Part No.	Power Supply	Clock Frequency	Max Data Rate	interface	Package
HY5DV281622DT-33		300MHz	600Mbps/pin		
HY5DV281622DT-36	VDD=3.3V	275MHz	550Mbps/pin		400mil 66nin
HY5DV281622DT-4	VDD=3.5V VDD0=2.5V	250MHz	500Mbps/pin	SSTL-2	400mil 66pin TSOP-II
HY5DV281622DT-5	VDDQ-2.5V	200MHz	400Mbps/pin		1501 11
HY5DV281622DT-6		166MHz	333Mbps/pin		



PIN CONFIGURATION



ROW and COLUMN ADDRESS TABLE

Items	8Mx16
Organization	2M x 16 x 4banks
Row Address	A0 ~ A11
Column Address	A0 ~ A8
Bank Address	BA0, BA1
Auto Precharge Flag	A10
Refresh	4K



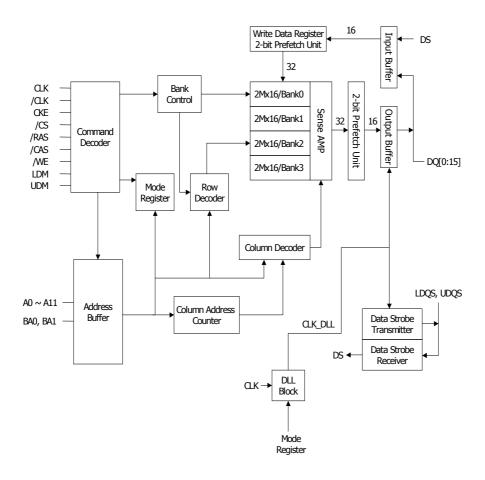
PIN DESCRIPTION

PIN	TYPE	DESCRIPTION
CK, /CK	Input	Clock: CK and /CK are differential clock inputs. All address and control input signals are sampled on the crossing of the positive edge of CK and negative edge of /CK. Output (read) data is referenced to the crossings of CK and /CK (both directions of crossing).
CKE	Input	Clock Enable: CKE HIGH activates, and CKE LOW deactivates internal clock signals, and device input buffers and output drivers. Taking CKE LOW provides PRECHARGE POWER DOWN and SELF REFRESH operation (all banks idle), or ACTIVE POWER DOWN (row ACTIVE in any bank). CKE is synchronous for POWER DOWN entry and exit, and for SELF REFRESH entry. CKE is asynchronous for SELF REFRESH exit, and for output disable. CKE must be maintained high throughout READ and WRITE accesses. Input buffers, excluding CK, /CK and CKE are disabled during POWER DOWN. Input buffers, excluding CKE are disabled during SELF REFRESH. CKE is an SSTL_2 input, but will detect an LVCMOS LOW level after Vdd is applied.
/CS	Input	Chip Select: Enables or disables all inputs except CK, /CK, CKE, DQS and DM. All commands are masked when CS is registered high. CS provides for external bank selection on systems with multiple banks. CS is considered part of the command code.
BAO, BA1	Input	Bank Address Inputs: BA0 and BA1 define to which bank an ACTIVE, Read, Write or PRE-CHARGE command is being applied.
A0 ~ A11	Input	Address Inputs: Provide the row address for ACTIVE commands, and the column address and AUTO PRECHARGE bit for READ/WRITE commands, to select one location out of the memory array in the respective bank. A10 is sampled during a precharge command to determine whether the PRECHARGE applies to one bank (A10 LOW) or all banks (A10 HIGH). If only one bank is to be precharged, the bank is selected by BA0, BA1. The address inputs also provide the op code during a MODE REGISTER SET command. BA0 and BA1 define which mode register is loaded during the MODE REGISTER SET command (MRS or EMRS).
/RAS, /CAS, /WE	Input	Command Inputs: /RAS, /CAS and /WE (along with /CS) define the command being entered.
LDM, UDM	Input	Input Data Mask: DM(LDM,UDM) is an input mask signal for write data. Input data is masked when DM is sampled HIGH along with that input data during a WRITE access. DM is sampled on both edges of DQS. Although DM pins are input only, the DM loading matches the DQ and DQS loading. LDM corresponds to the data on DQ0-Q7; UDM corresponds to the data on DQ8-Q15.
LDQS, UDQS	I/O	Data Strobe: Output with read data, input with write data. Edge aligned with read data, centered in write data. Used to capture write data. LDQS corresponds to the data on DQ0-Q7; UDQS corresponds to the data on DQ8-Q15.
DQ0 ~ DQ15	I/O	Data input / output pin : Data Bus
VDD/VSS	Supply	Power supply for internal circuits and input buffers.
VDDQ/VSSQ	Supply	Power supply for output buffers for noise immunity.
VREF	Supply	Reference voltage for inputs for SSTL interface.
NC	NC	No connection.



FUNCTIONAL BLOCK DIAGRAM

4Banks x 2Mbit x 16 I/O Double Data Rate Synchronous DRAM





SIMPLIFIED COMMAND TRUTH TABLE

Comman	ıd	CKEn-1	CKEn	cs	RAS	CAS	WE	ADDR	A10/ AP	ВА	Note
Extended Mode Re	egister Set	Н	Х	L	L	L	L		OP code		1,2
Mode Registe	er Set	Н	Х	L	L	L	L		OP code		1,2
Device Dese	elect	Н	Х	Н	Х	Х	Х		Х		1
No Operati	ion	''	^	L	Н	Н	Н		^		1
Bank Activ	ve	Н	Х	L	L	Н	Н	R	A	٧	1
Read		Н	Х	L	Н	L	L H	CA	L	٧	1
Read with Autop	recharge	''	^	L	11	L	""	CA	Н	V	1,3
Write		Н	Х	L	Н	L	L	CA	L	v	1
Write with Autop	Write with Autoprecharge		^	L	''	_	L	CA	Н	v	1,4
Precharge All	Precharge All Banks		Х	L	L	Н	L	Х	Н	Х	1,5
Precharge select	ed Bank	Н	, A	-	_		_	^	L	٧	1
Read Burst S	Stop	Н	Х	L	Н	Н	L		Х		1
Auto Refre	esh	Н	Н	L	L	L	Н		Х		1
	Entry	Н	L	L	L	L	Н				1
Self Refresh	Exit	L	Н	Н	Х	Х	Х		Χ		1
	LAIC	_	.,	L	Н	Н	Н				1
	Entry	Н	L	Н	Х	Х	Х				1
Precharge Power	Lindy		_	L	Н	Н	Н		X		1
Down Mode	Exit	L	Н	Н	Х	Х	Х		Λ		1
LXIC				L	Н	Н	Н				1
A 11 B	Entry	Н	L	Н	Х	Х	Х				1
Active Power Down Mode	Lifely			L	V	V	V		Χ		1
	Exit	L	Н)	Κ					1

(H=Logic High Level, L=Logic Low Level, X=Don't Care, V=Valid Data Input, OP Code=Operand Code, NOP=No Operation)

Note:

- 1. LDM/UDM states are Don't Care. Refer to below Write Mask Truth Table.
- 2. OP Code(Operand Code) consists of A0~A11 and BA0~BA1 used for Mode Register setting during Extended MRS or MRS. Before entering Mode Register Set mode, all banks must be in a precharge state and MRS command can be issued after tRP period from Prechagre command.
- 3. If a Read with Autoprecharge command is detected by memory component in CK(n), then there will be no command presented to activated bank until CK(n+BL/2+tRP).
- 4. If a Write with Autoprecharge command is detected by memory component in CK(n), then there will be no command presented to activated bank until CK(n+BL/2+1+tDPL+tRP). Last Data-In to Prechage delay(tDPL) which is also called Write Recovery Time (tWR) is needed to guarantee that the last data has been completely written.
- 5. If A10/AP is High when Precharge command being issued, BA0/BA1 are ignored and all banks are selected to be precharged.



WRITE MASK TRUTH TABLE

Function	CKEn-1	CKEn	/CS, /RAS, /CAS, /WE	LDM	UDM	ADDR	A10/ AP	ВА	Note
Data Write	Н	Х	Х	L	L		Χ		1,2
Data-In Mask	Н	Х	Х	Н	Н		Х		1,2
Lower Byte Write / Upper Byte-In Mask	Н	Х	Х	L	Н		Х		1,2
Upper Byte Write / Lower Byte-In Mask	Н	Х	Х	Н	L		Х		1,2

Note:

1. Write Mask command masks burst write data with reference to LDQS/UDQS(Data Strobes) and it is not related with read data.

2. LDM and UDM control lower byte(DQ0~7) and Upper byte(DQ8~15) respectively.



OPERATION COMMAND TRUTH TABLE - I

Current State	/CS	/RAS	/CAS	/WE	Address	Command	Action
	Н	Х	Х	Х	Х	DSEL	NOP or power down ³
	L	Н	Н	Н	Х	NOP	NOP or power down ³
	L	Н	Н	L	Х	BST	ILLEGAL ⁴
	L	Н	L	Н	BA, CA, AP	READ/READAP	ILLEGAL ⁴
IDLE	L	Н	L	L	BA, CA, AP	WRITE/WRITEAP	ILLEGAL ⁴
	L	L	Н	Н	BA, RA	ACT	Row Activation
	L	L	Н	L	BA, AP	PRE/PALL	NOP
	L	L	L	Н	Х	AREF/SREF	Auto Refresh or Self Refresh ⁵
	L	L	L	L	OPCODE	MRS	Mode Register Set
	Н	Х	Х	Х	Х	DSEL	NOP
	L	Н	Н	Н	Х	NOP	NOP
	L	Н	Н	L	Х	BST	ILLEGAL ⁴
ROW	L	Н	L	Н	BA, CA, AP	READ/READAP	Begin read : optional AP ⁶
	L	Н	L	L	BA, CA, AP	WRITE/WRITEAP	Begin write : optional AP ⁶
ACTIVE	L	L	Н	Н	BA, RA	ACT	ILLEGAL ⁴
	L	L	Н	L	BA, AP	PRE/PALL	Precharge ⁷
	L	L	L	Н	Х	AREF/SREF	ILLEGAL ¹¹
	L	L	L	L	OPCODE	MRS	ILLEGAL ¹¹
	Н	Х	Х	Х	Х	DSEL	Continue burst to end
	L	Н	Н	Н	Х	NOP	Continue burst to end
	L	Н	Н	L	Х	BST	Terminate burst
	L	Н	L	Н	BA, CA, AP	READ/READAP	Term burst, new read:optional AP ⁸
READ	L	Н	L	L	BA, CA, AP	WRITE/WRITEAP	ILLEGAL
	L	L	Н	Н	BA, RA	ACT	ILLEGAL ⁴
	L	L	Н	L	BA, AP	PRE/PALL	Term burst, precharge
	L	L	L	Н	Х	AREF/SREF	ILLEGAL ¹¹
	L	L	L	L	OPCODE	MRS	ILLEGAL ¹¹
	Н	Х	Х	Х	Х	DSEL	Continue burst to end
	L	Н	Н	Н	X	NOP	Continue burst to end
WRITE	L	Н	Н	L	Х	BST	ILLEGAL ⁴
	L	Н	L	Н	BA, CA, AP	READ/READAP	Term burst, new read:optional AP ⁸
	L	Н	L	L	BA, CA, AP	WRITE/WRITEAP	Term burst, new write:optional AP



OPERATION COMMAND TRUTH TABLE - II

Current State	/CS	/RAS	/CAS	/WE	Address	Command	Action
	L	L	Н	Н	BA, RA	ACT	ILLEGAL ⁴
WOTE	L	L	Н	L	BA, AP	PRE/PALL	Term burst, precharge
WRITE	L	L	L	Н	Х	AREF/SREF	ILLEGAL ¹¹
	L	L	L	L	OPCODE	MRS	ILLEGAL ¹¹
	Н	Х	Х	Х	Х	DSEL	Continue burst to end
	L	Н	Н	Н	Х	NOP	Continue burst to end
	L	Н	Н	L	Х	BST	ILLEGAL
READ	L	Н	L	Н	BA, CA, AP	READ/READAP	ILLEGAL ¹⁰
WITH AUTOPRE-	L	Н	L	L	BA, CA, AP	WRITE/WRITEAP	ILLEGAL ¹⁰
CHARGE	L	L	Н	Н	BA, RA	ACT	ILLEGAL ^{4,10}
	L	L	Н	L	BA, AP	PRE/PALL	ILLEGAL ^{4,10}
	L	L	L	Н	Х	AREF/SREF	ILLEGAL ¹¹
	L	L	L	L	OPCODE	MRS	ILLEGAL ¹¹
	Н	Х	Х	Х	Х	DSEL	Continue burst to end
	L	Н	Н	Н	Х	NOP	Continue burst to end
	L	Н	Н	L	Х	BST	ILLEGAL
WRITE	L	Н	L	Н	BA, CA, AP	READ/READAP	ILLEGAL ¹⁰
AUTOPRE- CHARGE	L	Н	L	L	BA, CA, AP	WRITE/WRITEAP	ILLEGAL ¹⁰
CHARGE	L	L	Н	Н	BA, RA	ACT	ILLEGAL ^{4,10}
	L	L	Н	L	BA, AP	PRE/PALL	ILLEGAL ^{4,10}
	L	L	L	Н	Х	AREF/SREF	ILLEGAL ¹¹
	L	L	L	L	OPCODE	MRS	ILLEGAL ¹¹
	Н	Х	Х	Х	Х	DSEL	NOP-Enter IDLE after tRP
	L	Н	Н	Н	Х	NOP	NOP-Enter IDLE after tRP
	L	Н	Н	L	Х	BST	ILLEGAL ⁴
	L	Н	L	Н	BA, CA, AP	READ/READAP	ILLEGAL ^{4,10}
PRE- CHARGE	L	Н	L	L	BA, CA, AP	WRITE/WRITEAP	ILLEGAL ^{4,10}
S 4 (OL	L	L	Н	Н	BA, RA	ACT	ILLEGAL ^{4,10}
	L	L	Н	L	BA, AP	PRE/PALL	NOP-Enter IDLE after tRP
	L	L	L	Н	X	AREF/SREF	ILLEGAL ¹¹
	L	L	L	L	OPCODE	MRS	ILLEGAL ¹¹



OPERATION COMMAND TRUTH TABLE - III

Current State	/CS	/RAS	/CAS	/WE	Address	Command	Action
	Н	Х	Х	Х	Х	DSEL	NOP - Enter ROW ACT after tRCD
	L	Н	Н	Н	Х	NOP	NOP - Enter ROW ACT after tRCD
	L	Н	Н	L	X	BST	ILLEGAL ⁴
	L	Н	L	Н	BA, CA, AP	READ/READAP	ILLEGAL ^{4,10}
ROW ACTIVATING	L	Н	L	L	BA, CA, AP	WRITE/WRITEAP	ILLEGAL ^{4,10}
ACTIVATIO	L	L	Н	Н	BA, RA	ACT	ILLEGAL ^{4,9,10}
	L	L	Н	L	BA, AP	PRE/PALL	ILLEGAL ^{4,10}
	L	L	L	Н	X	AREF/SREF	ILLEGAL ¹¹
	L	L	L	L	OPCODE	MRS	ILLEGAL ¹¹
	Н	Х	Х	Х	Х	DSEL	NOP - Enter ROW ACT after tWR
	L	Н	Н	Н	Х	NOP	NOP - Enter ROW ACT after tWR
	L	Н	Н	L	X	BST	ILLEGAL ⁴
	L	Н	L	Н	BA, CA, AP	READ/READAP	ILLEGAL
WRITE RECOVERING	L	Н	L	L	BA, CA, AP	WRITE/WRITEAP	ILLEGAL
RECOVERING	L	L	Н	Н	BA, RA	ACT	ILLEGAL ^{4,10}
	L	L	Н	L	BA, AP	PRE/PALL	ILLEGAL ^{4,11}
	L	L	L	Н	X	AREF/SREF	ILLEGAL ¹¹
	L	L	L	L	OPCODE	MRS	ILLEGAL ¹¹
	Н	Х	Χ	Χ	Х	DSEL	NOP - Enter precharge after tDPL
	L	Н	Н	Н	Х	NOP	NOP - Enter precharge after tDPL
	L	Н	Н	L	Х	BST	ILLEGAL ⁴
WRITE	L	Н	L	Н	BA, CA, AP	READ/READAP	ILLEGAL ^{4,8,10}
RECOVERING WITH	L	Н	L	L	BA, CA, AP	WRITE/WRITEAP	ILLEGAL ^{4,10}
AUTOPRE- CHARGE	L	L	Н	Н	BA, RA	ACT	ILLEGAL ^{4,10}
	L	L	Н	L	BA, AP	PRE/PALL	ILLEGAL ^{4,11}
	L	L	L	Н	Х	AREF/SREF	ILLEGAL ¹¹
	L	L	L	L	OPCODE	MRS	ILLEGAL ¹¹
	Н	Х	Х	Х	Х	DSEL	NOP - Enter IDLE after tRC
DEEDECLITAGE	L	Н	Н	Н	X	NOP	NOP - Enter IDLE after tRC
REFRESHING	L	Н	Н	L	X	BST	ILLEGAL ¹¹
	L	Н	L	Н	BA, CA, AP	READ/READAP	ILLEGAL ¹¹



OPERATION COMMAND TRUTH TABLE - IV

Current State	/CS	/RAS	/CAS	/WE	Address	Command	Action
	L	Н	L	L	BA, CA, AP	WRITE/WRITEAP	ILLEGAL ¹¹
	L	L	Н	Н	BA, RA	ACT	ILLEGAL ¹¹
WRITE	L	L	Н	L	BA, AP	PRE/PALL	ILLEGAL ¹¹
	L	L	L	Н	Х	AREF/SREF	ILLEGAL ¹¹
	L	L	L	L	OPCODE	MRS	ILLEGAL ¹¹
	Н	Х	Х	Х	Х	DSEL	NOP - Enter IDLE after tMRD
	L	Н	Н	Н	Х	NOP	NOP - Enter IDLE after tMRD
	L	Н	Н	L	Х	BST	ILLEGAL ¹¹
MODE	L	Н	L	Н	BA, CA, AP	READ/READAP	ILLEGAL ¹¹
REGISTER	L	Н	L	L	BA, CA, AP	WRITE/WRITEAP	ILLEGAL ¹¹
ACCESSING	L	L	Н	Н	BA, RA	ACT	ILLEGAL ¹¹
	L	L	Н	L	BA, AP	PRE/PALL	ILLEGAL ¹¹
	L	L	L	Н	Х	AREF/SREF	ILLEGAL ¹¹
	L	L	L	L	OPCODE	MRS	ILLEGAL ¹¹

Note

- 1. H Logic High Level, L Logic Low Level, X Don't Care, V Valid Data Input, BA - Bank Address, AP - AutoPrecharge Address, CA - Column Address, RA - Row Address, NOP - NO Operation.
- 2. All entries assume that CKE was active(high level) during the preceding clock cycle.
- 3. If both banks are idle and CKE is inactive(low level), then in power down mode.
- 4. Illegal to bank in specified state. Function may be legal in the bank indicated by Bank Address(BA) depending on the state of that bank.
- 5. If both banks are idle and CKE is inactive(low level), then self refresh mode.
- 6. Illegal if tRCD is not met.
- 7. Illegal if tRAS is not met.
- 8. Must satisfy bus contention, bus turn around, and/or write recovery requirements.
- 9. Illegal if tRRD is not met.
- 10. Illegal for single bank, but legal for other banks in multi-bank devices.
- 11. Illegal for all banks.



CKE FUNCTION TRUTH TABLE

Current State	CKEn- 1	CKEn	/cs	/RAS	/CAS	/WE	/ADD	Action
	Н	Х	Х	Х	Х	Х	Х	INVALID
	L	Н	Н	Х	Х	Х	Х	Exit self refresh, enter idle after tSREX
SELF	L	Н	L	Н	Н	Н	Х	Exit self refresh, enter idle after tSREX
REFRESH ¹	L	Н	L	Н	Н	L	Х	ILLEGAL
	L	Н	L	Н	L	Х	Х	ILLEGAL
	L	Н	L	L	Х	Х	Х	ILLEGAL
	L	L	Х	Х	Х	Х	Х	NOP, continue self refresh
	Н	Х	Х	Х	Х	Х	Х	INVALID
	L	Н	Н	Х	Х	Х	Х	Exit power down, enter idle
DOWED	L	Н	L	Н	Н	Н	Х	Exit power down, enter idle
POWER DOWN ²	L	Н	L	Н	Н	L	Х	ILLEGAL
	L	Н	L	Н	L	Х	Х	ILLEGAL
	L	Н	L	L	Х	Х	Х	ILLEGAL
	L	L	Х	Х	Х	Х	Х	NOP, continue power down mode
	Н	Н	Х	Х	Х	Х	Х	See operation command truth table
	Н	L	L	L	L	Н	Х	Enter self refresh
	Н	L	Н	Х	Х	Х	Х	Exit power down
ALL DANKS	Н	L	L	Н	Н	Н	Х	Exit power down
ALL BANKS IDLE ⁴	Н	L	L	Н	Н	L	Х	ILLEGAL
1511	Н	L	L	Н	L	Х	Х	ILLEGAL
	Н	L	L	L	Н	Х	Х	ILLEGAL
	Н	L	L	L	L	L	Х	ILLEGAL
	L	L	Х	Х	Х	Х	Х	NOP
ANIX CTATE	Н	Н	Х	Х	Х	Х	Х	See operation command truth table
ANY STATE OTHER	Н	L	Χ	Х	Х	Χ	Х	ILLEGAL ⁵
THAN ABOVE	L	Н	Х	Х	Х	Х	Х	INVALID
ADOVL	L	L	Χ	Х	Х	Х	Х	INVALID

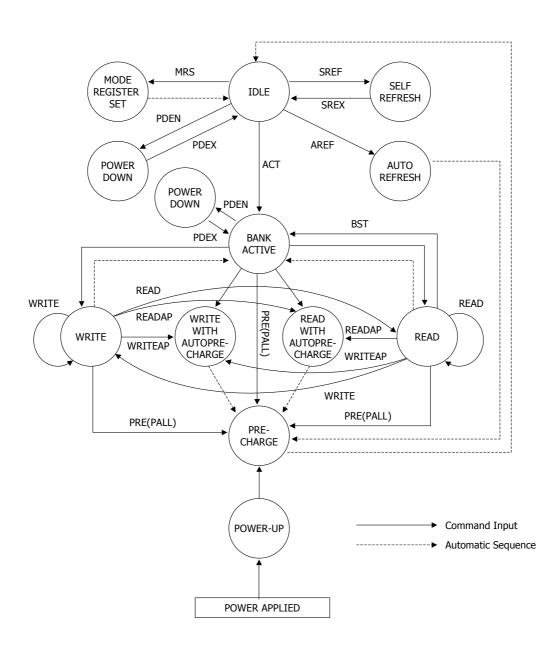
Note:

When CKE=L, all DQ and DQS must be in Hi-Z state.

- 1. CKE and /CS must be kept high for a minimum of 200 stable input clocks before issuing any command.
- 2. All command can be stored after 2 clocks from low to high transition of CKE.
- 3. Illegal if CK is suspended or stopped during the power down mode.
- 4. Self refresh can be entered only from the all banks idle state.
- 5. Disabling CK may cause malfunction of any bank which is in active state.



SIMPLIFIED STATE DIAGRAM





POWER-UP SEQUENCE AND DEVICE INITIALIZATION

DDR SDRAMs must be powered up and initialized in a predefined manner. Operational procedures other than those specified may result in undefined operation. Except for CKE, inputs are not recognized as valid until after VREF is applied. CKE is an SSTL_2 input, but will detect an LVCMOS LOW level after VDD is applied. Maintaining an LVCMOS LOW level on CKE during power-up is required to guarantee that the DQ and DQS outputs will be in the High-Z state, where they will remain until driven in normal operation (by a read access). After all power supply and reference voltages are stable, and the clock is stable, the DDR SDRAM requires a 200us delay prior to applying an executable command.

Once the 200us delay has been satisfied, a DESELECT or NOP command should be applied, and CKE should be brought HIGH. Following the NOP command, a PRECHARGE ALL command should be applied. Next a EXTENDED MODE REGISTER SET command should be issued for the Extended Mode Register, to enable the DLL, then a MODE REGISTER SET command should be issued for the Mode Register, to reset the DLL, and to program the operating parameters. After the DLL reset, tXSRD(DLL locking time) should be satisfied for read command. After the Mode Register set command, a PRECHARGE ALL command should be applied, placing the device in the all banks idle state.

Once in the idle state, two AUTO REFRESH cycles must be performed. Additionally, a MODE REGISTER SET command for the Mode Register, with the reset DLL bit deactivated low (i.e. to program operating parameters without resetting the DLL) must be performed. Following these cycles, the DDR SDRAM is ready for normal operation.

1. Apply power - VDD, VDDQ, VTT, VREF in the following power up sequencing and attempt to maintain CKE at LVC-MOS low state. (All the other input pins may be undefined.

No power sequencing is specified during power up or power down given the following cirteria:

- VDD and VDDO are driven from a single power converter output.
- VTT is limited to 1.44V (reflecting VDDQ(max)/2 + 50mV VREF variation + 40mV VTT variation).
- VREF tracks VDDQ/2.
- A minimum resistance of 42 ohms (22 ohm series resistor + 22 ohm parallel resistor 5% tolerance) limits the input current from the VTT supply into any pin.

If the above criteria cannot be met by the system design, then the following sequencing and voltage relationship must be adhered to during power up:

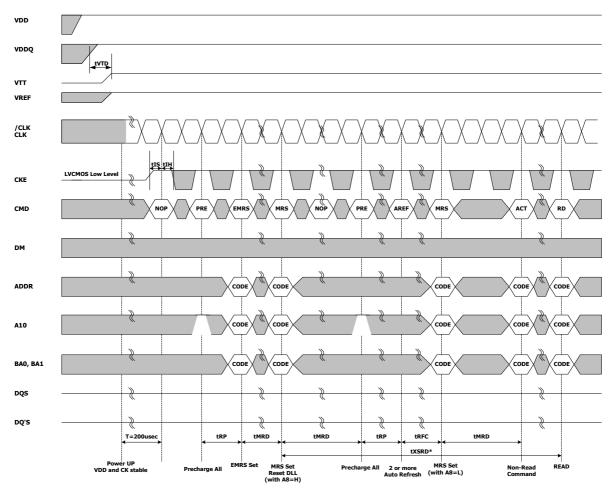
Voltage description	Sequencing	Voltage relationship to avoid latch-up					
VDDQ	After or with VDD	< VDD + 0.3V					
VTT	After or with VDDQ	< VDDQ + 0.3V					
VREF	After or with VDDQ	< VDDQ + 0.3V					

- 2. Start clock and maintain stable clock for a minimum of 200usec.
- 3. After stable power and clock, apply NOP condition and take CKE high.
- 4. Issue Extended Mode Register Set (EMRS) to enable DLL.
- 5. Issue Mode Register Set (MRS) to reset DLL and set device to idle state with bit A8=high. (An additional 200 cycles(tXSRD) of clock are required for locking DLL)
- 6. Issue Precharge commands for all banks of the device.



- 7. Issue 2 or more Auto Refresh commands.
- 8. Issue a Mode Register Set command to initialize the mode register with bit A8 = Low.

Power-Up Sequence

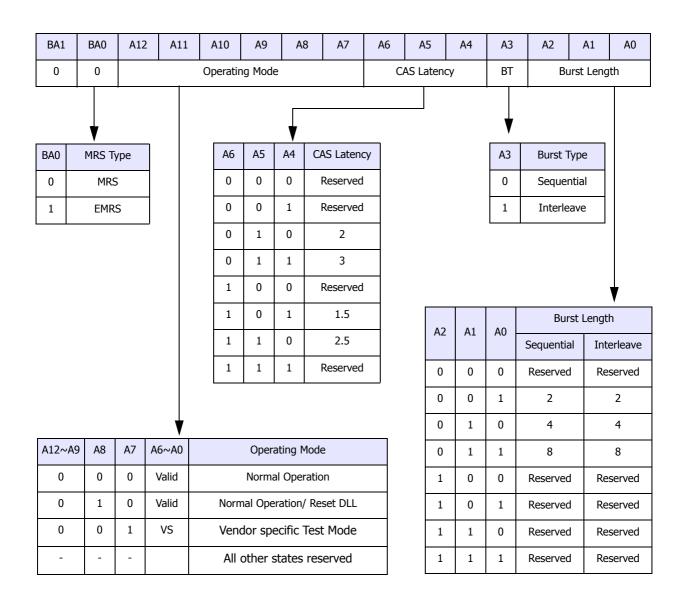


^{* 200} cycle(tXSRD) of CK are required (for DLL locking) before Read Command



MODE REGISTER SET (MRS)

The mode register is used to store the various operating modes such as /CAS latency, addressing mode, burst length, burst type, test mode, DLL reset. The mode register is program via MRS command. This command is issued by the low signals of /RAS, /CAS, /CS, /WE and BAO. This command can be issued only when all banks are in idle state and CKE must be high at least one cycle before the Mode Register Set Command can be issued. Two cycles are required to write the data in mode register. During the the MRS cycle, any command cannot be issued. Once mode register field is determined, the information will be held until resetted by another MRS command.





BURST DEFINITION

Burst Length	Starting Address (A2,A1,A0)	Sequential	Interleave
2	XX0	0, 1	0, 1
2		1, 0	1, 0
	X00	0, 1, 2, 3	0, 1, 2, 3
4	X01	1, 2, 3, 0	1, 0, 3, 2
'	X10	2, 3, 0, 1	2, 3, 0, 1
	X11	3, 0, 1, 2	3, 2, 1, 0
	000	0, 1, 2, 3, 4, 5, 6, 7	0, 1, 2, 3, 4, 5, 6, 7
	001	1, 2, 3, 4, 5, 6, 7, 0	1, 0, 3, 2, 5, 4, 7, 6
	010	2, 3, 4, 5, 6, 7, 0, 1	2, 3, 0, 1, 6, 7, 4, 5
Q.	011	3, 4, 5, 6, 7, 0, 1, 2	3, 2, 1, 0, 7, 6, 5, 4
	100	4, 5, 6, 7, 0, 1, 2, 3	4, 5, 6, 7, 0, 1, 2, 3
	101	5, 6, 7, 0, 1, 2, 3, 4	5, 4, 7, 6, 1, 0, 3, 2
	110	6, 7, 0, 1, 2, 3, 4, 5	6, 7, 4, 5, 2, 3, 0, 1
	111	7, 0, 1, 2, 3, 4, 5, 6	7, 6, 5, 4, 3, 2, 1, 0

BURST LENGTH & TYPE

Read and write accesses to the DDR SDRAM are burst oriented, with the burst length being programmable. The burst length determines the maximum number of column locations that can be accessed for a given Read or Write command. Burst lengths of 2, 4 or 8 locations are available for both the sequential and the interleaved burst types. Reserved states should not be used, as unknown operation or incompatibility with future versions may result.

When a Read or Write command is issued, a block of columns equal to the burst length is effectively selected. All accesses for that burst take place within this block, meaning that the burst wraps within the block if a boundary is reached. The block is uniquely selected by A1-Ai when the burst length is set to two, by A2-Ai when the burst length is set to four and by A3-Ai when the burst length is set to eight (where Ai is the most significant column address bit for a given configuration). The remaining (least significant) address bit(s) is (are) used to select the starting location within the block. The programmed burst length applies to both Read and Write bursts.

Accesses within a given burst may be programmed to be either sequential or interleaved; this is referred to as the burst type and is selected via bit A3. The ordering of accesses within a burst is determined by the burst length, the burst type and the starting column address, as shown in Burst Definitionon Table



CAS LATENCY

The Read latency or CAS latency is the delay in clock cycles between the registration of a Read command and the availability of the first burst of output data. The latency can be programmed 3 or 4 clocks.

If a Read command is registered at clock edge n, and the latency is m clocks, the data is available nominally coincident with clock edge n + m.

Reserved states should not be used as unknown operation or incompatibility with future versions may result.

DLL RESET

The DLL must be enabled for normal operation. DLL enable is required during power up initialization, and upon returning to normal operation after having disabled the DLL for the purpose of debug or evaluation. The DLL is automatically disabled when entering self refresh operation and is automatically re-enabled upon exit of self refresh operation. Any time the DLL is enabled, 200 clock cycles must occur to allow time for the internal clock to lock to the externally applied clock before an any command can be issued.

OUTPUT DRIVER IMPEDANCE CONTROL

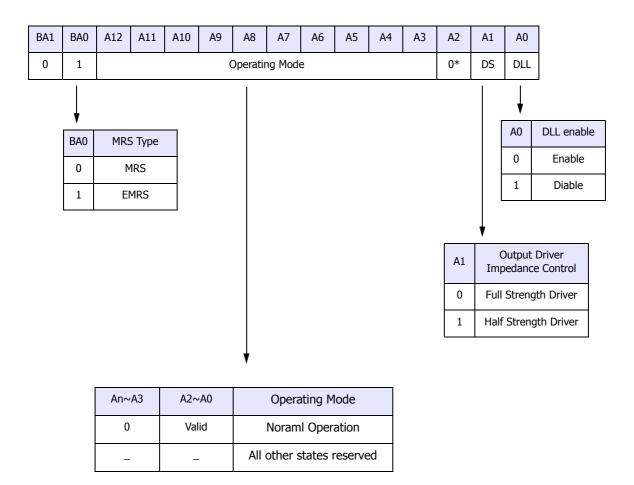
The HY5DV281622D supports Full, Half strength driver and Matched impedance driver, intended for lighter load and/or point-to-point environments. The Full drive strength for all output is specified to be SSTL_2, CLASS II. Half strength driver is to define about 50% of Full drive strength and Matched impedance driver, about 30% of Full drive strength.



EXTENDED MODE REGISTER SET (EMRS)

The Extended Mode Register controls functions beyond those controlled by the Mode Register; these additional functions include DLL enable/disable, output driver strength selection(optional). These functions are controlled via the bits shown below. The Extended Mode Register is programmed via the Mode Register Set command (BA0=1 and BA1=0) and will retain the stored information until it is programmed again or the device loses power.

The Extended Mode Register must be loaded when all banks are idle and no bursts are in progress, and the controller must wait the specified time before initiating any subsequent operation. Violating either of these requirements will result in unspecified operation.



^{*} This part do not support/QFC function, A2 must be programmed to Zero.



ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Rating	Unit
Ambient Temperature	TA	0 ~ 70	°C
Storage Temperature	TSTG	-55 ~ 125	°C
Voltage on Any Pin relative to VSS	VIN, VOUT	-0.5 ~ 3.6	V
Voltage on VDD relative to VSS	VDD	-0.5 ~ 3.6	V
Voltage on VDDQ relative to VSS	VDDQ	-0.5 ~ 3.6	V
Output Short Circuit Current	Ios	50	mA
Power Dissipation	PD	1	W
Soldering Temperature · Time	TSOLDER	260 · 10	°C ⋅ sec

Note: Operation at above absolute maximum rating can adversely affect device reliability

DC OPERATING CONDITIONS (TA=0 to 70°C, Voltage referenced to VSS = 0V)

Parameter	Symbol	Min	Тур.	Max	Unit	Note
Power Supply Voltage	VDD	3.15	3.3	3.45	V	
Power Supply Voltage	VDD	3.15	3.3	3.65	V	4
Power Supply Voltage	VDDQ	2.375	2.5	2.625	V	1
Power Supply Voltage	VDDQ	2.375	2.5	3.15	V	1,4
Input High Voltage	VIH	VREF + 0.15	-	VDDQ + 0.3	V	
Input Low Voltage	VIL	-0.3	-	VREF - 0.15	V	2
Termination Voltage	VTT	VREF - 0.04	VREF	VREF + 0.04	V	
Reference Voltage	VREF	0.49*VDDQ	0.5*VDDQ	0.51*VDDQ	V	3
Input Voltage Level, CK and CK inputs	VIN(DC)	-0.3	VDDQ+0.3	V		
Input Differential Voltage, CK and CK inputs	VID(DC)	0.36	VDDQ+0.6	V	4	
V-I Matching: Pullup to Pulldown Cur- rent Ratio	VI(RATIO)	0.71	1.4	-	5	
Input Leakage Current	ILI	-2	2	uA	6	
Output Leakage Current	ILO	-5	5	uA		
Output High Voltage	VOH	VTT + 0.76	-	V	IOL = -15.2mA	
Output Low Voltage	VOL	-	VTT - 0.76	V	IOL = +15.2mA	

Note:

- 1. VDDQ must not exceed the level of VDD.
- 2. VIL (min) is acceptable -1.5V AC pulse width with \leq 5ns of duration.
- 3. VREF is expected to be equal to 0.5*VDDQ of the transmitting device, and to track variations in the dc level of the same. Peak to peak noise on VREF may not exceed \pm 2% of the dc value.
- 4. Supports 300/275MHz
- 5. VID is the magnitude of the difference between the input level on CK and the input level on /CK.
- 6. The ratio of the pullup current to the pulldown current is specified for the same temperature and voltage, over the entire temper ature and voltage range, for device drain to source voltages from 0.25V to 1.0V. For a given output, it represents the maximum difference between pullup and pulldown drivers due to process variation. The full variation in the ratio of the maximum to minimum pullup and pulldown current will not exceed 1/7 for device drain to source voltages from 0.1 to 1.0.
- 7. VIN=0 to VDD, All other pins are not tested under VIN =0V. 2. DOUT is disabled, VOUT=0 to VDDQ



DC CHARACTERISTICS I (TA=0 to 70oC, Voltage referenced to Vss = 0V)

Parameter	Symbol	Min.	Max	Unit	Note
Input Leakage Current	ILI	-5	5	uA	1
Output Leakage Current	ILO	-5	5	uA	2
Output High Voltage	Voh	VTT + 0.76	-	V	IOH = -15.2mA
Output Low Voltage	VOL	-	VTT - 0.76	V	IOL = +15.2mA

Note: 1. VIN = 0 to 3.6V, All other pins are not tested under VIN = 0V. 2. DOUT is disabled, VOUT = 0 to 2.7V



DC CHARACTERISTICS II (TA=0 to 70°C, Voltage referenced to Vss = 0V)

Davamatav	Crossbal	Took Condition			Speed				Note
Parameter	Symbol	Test Condition	33	36	4	5	6	Unit	Note
Operating Current	IDD0	One bank; Active - Precharge; tRC=tRC(min); tCK=tCK(min); DQ,DM and DQS inputs changing twice per clock cycle; address and control inputs changing once per clock cycle	150	140	130	120	100	mA	
Operating Current	IDD1	One bank; Active - Read - Precharge; Burst=2; tRC=tRC(min); tCK=tCK(min); address and control inputs changing once per clock cycle; IOUT=0mA	170 150 140 130 110				mA		
Precharge Power Down Standby Current	IDD2P	All banks idle; Power down mode; CKE=Low, tCK=tCK(min)			20			mA	
Idle Standby Current	IDD2F	/CS=High, All banks idle; tCK=tCK(min); CKE=High; address and control inputs changing once per clock cycle. VIN=VREF for DQ, DQS and DM	90	80	70	60	50	mA	
Active Power Down Standby Current	IDD3P	One bank active; Power down mode ; CKE=Low, tCK=tCK(min)			20			mA	
Active Standby Current	IDD3N	/CS=HIGH; CKE=HIGH; One bank; Active- Precharge; tRC=tRAS(max); tCK=tCK(min); DQ, DM and DQS inputs changing twice per clock cycle; Address and other control inputs changing once per clock cycle	90	80	70	60	50	mA	
Operating Current	IDD4R	Burst=2; Reads; Continuous burst; One bank active; Address and control inputs changing once per clock cycle; tCK=tCK(min); IOUT=0mA	250	230	210	180	160	mA	
Operating Current	IDD4W	Burst=2; Writes; Continuous burst; One bank active; Address and control inputs changing once per clock cycle; tCK=tCK(min); DQ, DM and DQS inputs changing twice per clock cycle	210	190	170	150	140	mA	
Auto Refresh Current	IDD5	tRC=tRFC(min); All banks active	220	200	180	150	140	mA	
Self Refresh Current	IDD6	CKE=<0.2V; External clock on; tCK=tCK(min)			2	•		mA	
Operating Current - Four Bank Operation	IDD7	Four bank interleaving with BL=4	350	330	310	270	250	mA	



AC OPERATING CONDITIONS (TA=0 to 70°C, Voltage referenced to VSS = 0V)

Parameter	Symbol	Min	Max	Unit	Note
Input High (Logic 1) Voltage, DQ, DQS and DM signals	VIH(AC)	VREF + 0.35		V	
Input Low (Logic 0) Voltage, DQ, DQS and DM signals	VIL(AC)		VREF - 0.35	V	
Input Differential Voltage, CK and /CK inputs	VID(AC)	0.7	VDDQ + 0.6	V	1
Input Crossing Point Voltage, CK and /CK inputs	VIX(AC)	0.5*VDDQ-0.2	0.5*VDDQ+0.2	V	2

Note:

- 1. VID is the magnitude of the difference between the input level on CK and the input on CK.
- 2. The value of VIX is expected to equal 0.5*VDDQ of the transmitting device and must track variations in the DC level of the same.

AC OPERATING TEST CONDITIONS (TA=0 to 70°C, Voltage referenced to VSS = 0V)

Parameter	Value	Unit
Reference Voltage	VDDQ x 0.5	V
Termination Voltage	VDDQ x 0.5	V
AC Input High Level Voltage (VIH, min)	VREF + 0.35	V
AC Input Low Level Voltage (VIL, max)	VREF - 0.35	V
Input Timing Measurement Reference Level Voltage	VREF	V
Output Timing Measurement Reference Level Voltage	Vπ	V
Input Signal maximum peak swing	1.5	V
Input minimum Signal Slew Rate	1	V/ns
Termination Resistor (RT)	50	Ω
Series Resistor (RS)	25	Ω
Output Load Capacitance for Access Time Measurement (CL)	30	pF



AC Overshoot/Undershoot Specification for Address and Control Pins This specification is intended for devices with no clamp protection and is guaranteed by design

Parameter	Specification			
Parameter	DDR333	DDR200/266		
Maximum peak amplitude allowed for overshoot (See Figure 1):	1.5V	1.5V		
Maximum peak amplitude allowed for undershoot (See Figure 1):	1.5V	1.5V		
The area between the overshoot signal and VDD must be less than or equal to (See Figure 1):	4.5V - ns	4.5V - ns		
The area between the undershoot signal and GND must be less than or equal to (See Figure 1):	4.5V - ns	4.5V - ns		

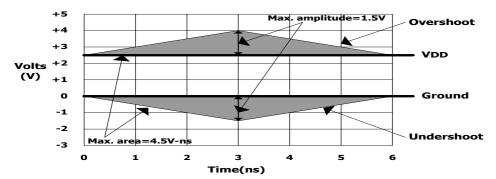


Figure 1: Address and Control AC Overshoot and Undershoot Definitio

Overshoot/Undershoot Specification for Data, Strobe, and Mask Pins

Parameter	Specif	ication
Farameter	DDR333	DDR200/266
Maximum peak amplitude allowed for overshoot (See Figure 2):	1.2V	1.2V
Maximum peak amplitude allowed for undershoot (See Figure 2):	1.2V	1.2V
The area between the overshoot signal and VDD must be less than or equal to (See Figure 2):	2.4V - ns	2.4V - ns
The area between the undershoot signal and GND must be less than or equal to (See Figure 2):	2.4V - ns	2.4V - ns

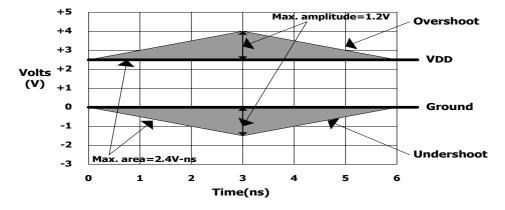


Figure 2: DQ/DM/DQS AC Overshoot and Undershoot Definition



AC CHARACTERISTICS - I (AC operating conditions unless otherwise noted)

Dawawataw		Complete	3	3	3	6	4	1	į	5	(5		
Parameter		Symbol	Min	Max	Unit	Note								
Row Cycle Time		tRC	18	-	16	-	15	-	12	-	11	-	CK	
Auto Refresh Row Cycle	Time	trFC	22	-	20	-	18	-	14	-	12	-	CK	
Row Active Time		tras	12	100K	11	100K	10	100K	8	100K	7	100K	CK	
Row Address to Column	Address	trcdrd	6	-	5	-	5	-	4	-	4	-	CK	
Delay		trcdwt	2	-	2	-	2	-	2	-	2	-	CK	
Row Active to Row Active	ve Delay	trrd	2	-	2	-	2	-	2	-	2	-	CK	
Column Address to Colu Address Delay	ımn	tCCD	1	-	1	-	1	-	1	-	1	-	СК	
Row Precharge Time		trp	6	-	5	-	5	-	4	-	4	-	CK	
Last Data-In to Precharge Delay (Write Recovery Time: tWR)		tDPL	3	-	3	-	3	1	3	ı	2	1	СК	
Last Data-In to Read Co	ommand	tDRL	2	-	2	-	2	-	2	-	2	-	CK	
Auto Precharge Write Re Precharge Time	covery+	tDAL	9	-	8	-	8	-	7	-	6	-	CK	
System Clock Cycle	CL = 4.0	tck	3.3	6.0	3.6	6.0	4.0	6.0	-	-	-	-	ns	
Time	CL = 3.0	tck	-	-	-	-	4.3	7.0	5.0	7.0	6.0	7.0	ns	
Clock High Level Width		tCH	0.45	0.55	0.45	0.55	0.45	0.55	0.45	0.55	0.45	0.55	CK	
Clock Low Level Width		tCL	0.45	0.55	0.45	0.55	0.45	0.55	0.45	0.55	0.45	0.55	CK	
Data-Out edge to Clock Skew	edge	tAC	-0.7	0.7	-0.7	0.7	-0.7	0.7	-0.7	0.7	-0.75	0.75	ns	
DQS-Out edge to Clock Skew	edge	tDQSCK	-0.7	0.7	-0.7	0.7	-0.7	0.7	-0.7	0.7	-0.75	0.75	ns	
DQS-Out edge to Data- Skew	Out edge	tDQSQ	-	0.4	-	0.4	-	0.4	-	0.45	-	0.5	ns	
Data-Out hold time from	n DQS	tQH	tHPmin -tQHS	-	ns	1, 6								
Clock Half Period		tHP	tCH/L min	-	ns	1, 5								
Data Hold Skew Factor		tQHS	-	0.4	-	0.4	-	0.4	-	0.75	-	0.75	ns	6
Input Setup Time		tIS	0.9	-	0.9	-	0.9	=	0.9	-	0.9	-	ns	2
Input Hold Time		tIH	0.9	-	0.9	-	0.9	-	0.9	-	0.9	-	ns	2



Parameter	Symbol	3	3	36		4		5		6		Unit	Nata
raiailletei	Syllibol	Min	Max	Unit	Note								
Write DQS High Level Width	tDQSH	0.4	0.6	0.4	0.6	0.4	0.6	0.4	0.6	0.4	0.6	CK	
Write DQS Low Level Width	tDQSL	0.4	0.6	0.4	0.6	0.4	0.6	0.4	0.6	0.4	0.6	CK	
Clock to First Rising edge of DQS-In	tDQSS	0.85	1.15	0.85	1.15	0.85	1.15	0.75	1.25	0.75	1.25	CK	
Data-In Setup Time to DQS-In (DQ & DM)	tDS	0.4	-	0.4	-	0.4	-	0.5	-	0.5	-	ns	3
Data-In Hold Time to DQS-In (DQ & DM)	tDH	0.4	-	0.4	-	0.4	-	0.5	-	0.5	-	ns	3
Read DQS Preamble Time	trpre	0.9	1.1	0.9	1.1	0.9	1.1	0.9	1.1	0.9	1.1	CK	
Read DQS Postamble Time	trpst	0.4	0.6	0.4	0.6	0.4	0.6	0.4	0.6	0.4	0.6	CK	
Write DQS Preamble Setup Time	twPres	0	-	0	-	0	-	0	-	0	-	ns	
Write DQS Preamble Hold Time	twpreh	1.5	-	1.5	-	1.5	-	1.5	-	1.5	-	ns	
Write DQS Postamble Time	twpst	0.4	0.6	0.4	0.6	0.4	0.6	0.4	0.6	0.4	0.6	CK	
Mode Register Set Delay	tMRD	3	-	3	-	3	-	2	-	2	-	CK	
Exit Self Refresh to Any Execute Command	txsc	200	-	200	-	200	-	200	-	200	-	CK	4
Power Down Exit Time	tPDEX	1tCK + tIS		1tCK + tIS	-	СК							
Average Periodic Refresh Interval	trefi	-	7.8	-	7.8	-	7.8	-	7.8	-	7.8	us	

Note:

- 1. This calculation accounts for tDQSQ(max), the pulse width distortion of on-chip circuit and jitter.
- 2. Data sampled at the rising edges of the clock: A0~A11, BA0~BA1, CKE, /CS, /RAS, /CAS, /WE.
- 3. Data latched at both rising and falling edges of Data Strobes(LDQS/UDQS): DQ, LDM/UDM.
- 4. Minimum of 200 cycles of stable input clocks after Self Refresh Exit command, where CKE is held high, is required to complete Self Refresh Exit and lock the internal DLL circuit of DDR SDRAM.
- 5. Min (tCL, tCH) refers to the smaller of the actual clock low time and the actual clock high time as provided to the device (i.e. this value can be greater than the minimum specification limits for tCL and tCH).
- 6. tHP = minimum half clock period for any given cycle and is defined by clock high or clock low (tCH, tCL). tQHS consists of tDQSQmax, the pulse width distortion of on-chip clock circuits, data pin to pin skew and output pattern effects, and p-channel to n-channel variation of the output drivers.
- 7. DQS, DM and DQ input slew rate is specified to prevent double clocking of data and preserve setup and hold times. Signal transitions through the DC region must be monotonic.



AC CHARACTERISTICS - II

Frequency	CL	tRC	tRFC	tRAS	tRCDRD	tRCDWR	tRP	tDAL	Unit
300MHz (3.3ns)	4	18	22	12	6	2	6	9	tCK
275MHz (3.6ns)	4	16	20	11	5	2	5	8	tCK
250MHz (4.0ns)	4	15	18	10	5	2	5	8	tCK
233MHz (4.3ns)	3	15	18	10	5	2	5	8	tCK
200MHz (5.0ns)	3	12	14	8	4	2	4	7	tCK
166MHz (6.0ns)	3	11	12	7	4	2	4	6	tCK



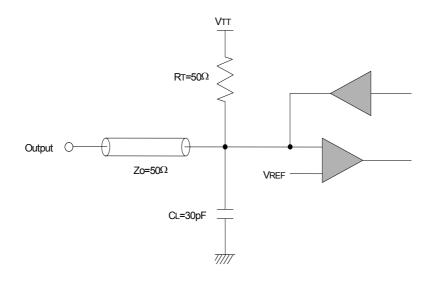
CAPACITANCE (TA=25°C, f=1MHz)

Parameter	Pin	Symbol	Min	Max	Unit
Input Clock Capacitance	CK, CK	ССК	2.0	3.0	pF
Input Capacitance	All other input-only pins	CIN	2.0	3.0	pF
Input / Output Capacitanc	DQ, DQS, DM	CIO	4.0	5.0	pF

Note:

- 1. VDD = min. to max., VDDQ = 2.3V to 2.7V, VODC = VDDQ/2, VOpeak-to-peak = 0.2V
- 2. Pins not under test are tied to GND.
- 3. These values are guaranteed by design and are tested on a sample basis only.

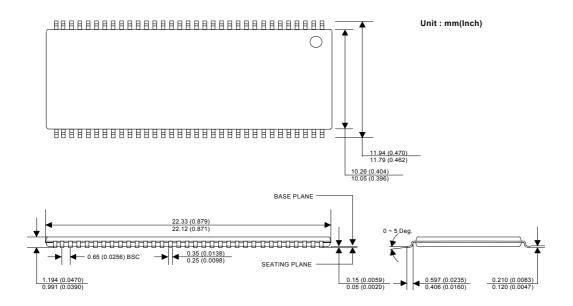
OUTPUT LOAD CIRCUIT





PACKAGE INFORMATION

400mil 66pin Thin Small Outline Package



Note: Package do not mold protrusion. Allowable protrusion of both sides is 0.4mm.